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Contents

v vii	Authors Conference Committee
	MEDICAL APPLICATIONS
11004 04	Use of equivalent wave field transform in evaluating dynamic thermal tomography of infrared breast images [11004-4]
11004 05	Detection of syrinx in thermographic images of canines with Chiari malformation using MATLAB CVIP toolbox GUI $[11004-5]$
	INDUSTRIAL APPLICATION
11004 06	Improving thermal substation inspections utilising machine learning [11004-6]
11004 07	Advanced signal processing applied to thermographic inspection of petrochemical furnaces [11004-7]
11004 08	Improvements in the design of thermal-infrared radiation thermometers and sensors [11004-8]
11004 09	Thermal conductivity of refractory coatings for foundry applications [11004-9]
11004 0A	The use of drones, thermography, and other optical measuring devices [11004-10]
	RESEARCH TOPICS
11004 OB	Research on the stability of readout circuit based on single grade OP-AMP for IR detector [11004-11]
11004 OD	A comparison study of additive manufacturing techniques applied to chalcogenide glass [11004-13]
	AEROSPACE APPLICATIONS
11004 OE	Estimation of delamination crack depth using passive thermography [11004-14]
11004 OF	Quadrupole simulations of thermographic inspections of impacted composites [11004-15]

11004 0G	Thermosonic imaging for rapid full-field nondestructive inspection of composite structures [11004-16]
11004 OH	Fatigue behaviour assessment of automated fiber placement composites by adopting the thermal signal analysis $[11004-17]$
11004 01	Autonomous systems thermographic NDT of composite structures [11004-18]
	NDT
11004 OJ	Flying-spot thermography: measuring the in-plane (an)isotropic thermal diffusivity of large and complex parts [11004-19]
11004 OK	Flying-spot thermography: sizing the thermal resistance of infinite vertical cracks [11004-20]
11004 OL	Flash and inductive thermography for CFRP inspection [11004-21]
11004 0M	The influence of the truncation window size on the quantitative thermographic results after a pulsed test on an aluminium sample: comparison among different post-processing algorithms [11004-22]
11004 ON	A new thermographic procedure for the non-destructive evaluation of RSW joints [11004-23]
11004 00	Study of the thermo-elastic stress analysis (TSA) sensitivity in the evaluation of residual stress in non-ferrous metal [11004-25]
11004 0Q	Low cost high resolution transient thermography imaging based on equivalent wave field transform [11004-100]
	POSTER SESSION
11004 OS	Development of a new methodology for thermal image reconstruction [11004-30]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Avdelidis, N. P., 01 Batsale, J. C., 0J Bedoya, A., OJ Bison, Paolo, 09 Carrasco, Joaquin, 06 Chen, Yongping, 0B Cotton, Ian, 06 Cuellar, J., 05

D'Accardi, Ester, 0M, 0N

Deane, S., Ol Deegan, J., 0D De Finis, R., 0H, 0O Di Carolo, F., 0O

Eppeldauer, George P., 08

Exarchos, D. A., 0S Ferrarini, Giovanni, 09

Galietti, Umberto, 0H, 0M, 0N, 0O

Gardner, Richard, 06 Gershenson, J., 04 Gershenson, Meir, 04, 0Q González, J., 0J, 0K Hassinen, Marko, 0A Howell, Patricia A., 0F Huana, Zhiwei, OB Huot, Alexandrine, 07 Ibarra-Castanedo, C., 01 Jackson, Wade C., 0E Karlapalem, A., 05 Kauppinen, Timo, 0A

Khromchenko, Vladimir B., 08

Kordatos, E. Z., OS Kordatou, T. Z., OS Li, Wuying, 0B Lin, Bin, OG Lindberg, G. P., 0D Long, Michael, 0G Lopez, Fernando, 07

Maldague, X. P. V., 01

Marino, D. J., 05

Matikas, T. E., OS

Mendioroz, A., 0J, 0K

Musgraves, J. D., 0D

Oswald-Tranta, Beate, OL

Palumbo, Davide, 0M, 0N, 0O

Podd, Frank, 06 Posio, Mikko, 0A Pradere, C., 0J Ramsey, J. L., 0D

Rose, Cheryl A., 0E

Rossi, Stefano, 09 Sackman, J., 05 Salazar, A., OJ, OK Savolainen, Marko, 0A Schledjewski, Ralf, OL Siikanen, Sami, OA Skog, Gedi, 0A Sommier, A., 0J Stockton, Greg, 0A Straker, Alastair, 06

Tamborrino, Rosanna, OM Tsourdos, A., OI Tuschl, Christoph, 0L Tzitzilonis, V., 01 Umbaugh, S. E., 05 Wachtel, P. F., 0D Williamson, A., 01 Winfree, William P., 0F

Xiang, Dan, 0G Xu, Xina, 0B

Yazdani Nezhad, H., 01 Yoon, Howard W., 08 Yuan, Honghui, OB

Zalameda, Joseph N., OE, OF

Zhang, H., Ol

Zhong, Yanping, OB

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3 Industrial Application

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4 Research Topics

Jaap de Vries, FM Global (United States)
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